Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/774,039	MIKULA, MITCHELL B.
Examiner	Art Unit
Le Nguyen	2174

SEARCHED						
Class	Subclass	Date	Examiner			
715	734	2/18/2007	LVN			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
US-PGPub, USPAT: 715/734		2/18/2007	LVN		

STRATEGY)	<u> </u>
DATE	EXMR
2/19/2007	LVN
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4/11/2007	LVN
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